

# *Biometric Consortium 2005 Conference*

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**Dr. Hale Kim**

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**Topic:** Fingerprint Verification Testing Scenarios for Multi-impression Enrollment and Template Adaptation

**Biography:** Dr. Hale Kim is currently a professor of School of Information & Communication Engineering at Inha University and a member of Biometrics Engineering Research Center (BERC) at Yonsei University, Seoul, Korea. He also chairs the testing and evaluation working group of Korea Biometrics Association. He actively participates in the WG5 (Testing and Reporting) of ISO/IEC JTC1-SC37.

He is also a member of advisory committees of Korean governmental organizations such as Korea Information Security Agency, Ministry of Information and Communication, National Intelligence Service, and Electronics and Telecommunication Research Institute.

His areas of expertise include digital signal and image processing, computer vision, and pattern recognition. His recent research works focus on development of fingerprint recognition algorithms, comparative test and evaluation of performance of various fingerprint readers, and data fusion for multiple biometrics.

He received a B.S. degree in Control and Measurement Engineering from Seoul National University, Seoul, Korea, and an M.S. degree and a Ph.D. degree in Electrical and Computer Engineering from Purdue University, West Lafayette, IN.